# µShape Interferometer Software

The perfect user-interface for your interferometer

General features

- For topography measurement of flat, spherical, cylindrical, toric and aspherical surfaces or wave fronts
- Application area in production, laboratory and research
- Wide range of Add-on modules for customized demands
- Clear and well-structured interface
- For all Windows® versions
- Control measurements and display results
- Store and document all measurement raw data and analysis parameters
- Maximum transparency and traceability

Upgrade laboratory interferometer

- With GenPack (generic software package for phase-measuring interferometers) useable with most other interferometers
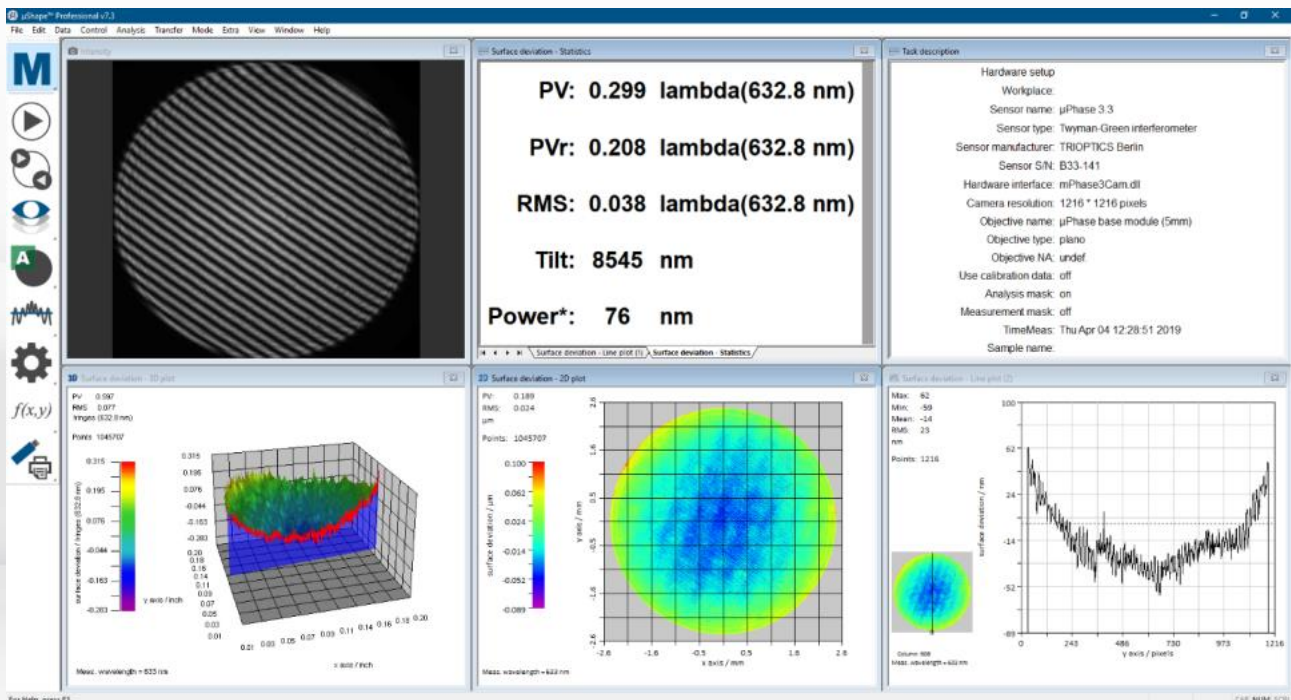
For further information please contact support@trioptics-berlin.com.

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Features of the µShape measuring and analysis software (selection)

- Different user levels with different access rights
- Shortcuts for most used program functions
- Comprehensive context-sensitive direct help
- Various program modes enable the separate visualization of calibration and measurement processes and its parameter with an integrated live camera image
- Automatic updates of displays and images after every change of analysis parameters or new measurement, allows re-analyses of measurements without new measurement
- Easily pre-configured templates for a wide range of measuring tasks and analyses containing all parameters and settings including the configuration of screen display
- Graphic windows can be stored in several graphic formats
- Export of individual parameters or of selected data fields as text, binary or other common file formats (e.g. QED, Zygo XYZ, DigitalSurf) for external processing
- The measuring results are presented as parameters or graphically as 2D, 3D, histogram or line graph
- Configurable measurement reports show results at a glance
- Several common analyses like Zernike, Seidel, ISO, Legendre, Slope

Add-ons (selection)

- Access control and configuration of add-on modules by dongle
- Analysis of aspherical, cylindrical or toric surfaces in spherical or CGH setups
- External interface for controlling the interferometer by external programs, e.g. in automated systems
- MTF analysis of focal or afocal optical components and systems
- Measuring multiple apertures in one shot, e.g. on polishing heads
- Statistical analysis of multiple sub-apertures at the same time (MultiStat) including tolerating and pass/fail indication
- Prism and wedge measurement and analysis
- Consideration of known sample deviations e.g. deviations caused by the optical design (Sample Normal Data)
- Analysis of the tool offset of lathe machines
- Analysis of wafer plates
- Static fringe analysis for fast one-shot measurements in instable environments